

FALAPHEL SER28

Project Status

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June 27th, 2023

FALAPHEL SER28 Devices

- SER28_V1 (submitted in May 2022)
 - Single Data Rate (SDR) + Common Mode Logic (CML)
 - BIST + Parallel LVDS Input Port
 - Target Data Rate = 10Gbps
 - Validated up to 7Gbps - Failures at higher data rates under investigations (test setup issues?)
 - TID Test (INFN-Pisa) => Recoverable effects on BER
 - SEU Test (LNL) => June 29th/30th
- SER28_V2 (submitted in April 2023)
 - Double Data Rate (DDR) + Common Mode Logic (CML)
 - BIST, No Parallel Input Port
 - Target Data Rate = 20Gbps
- SER28_V3 (submission Q4-2023 or Q1-2024)
 - Double Data Rate (DDR) + CMOS
 - BIST, No Parallel Input Port
 - Target Data Rate = 25Gbps

SER_V1 (Test and Characterization)

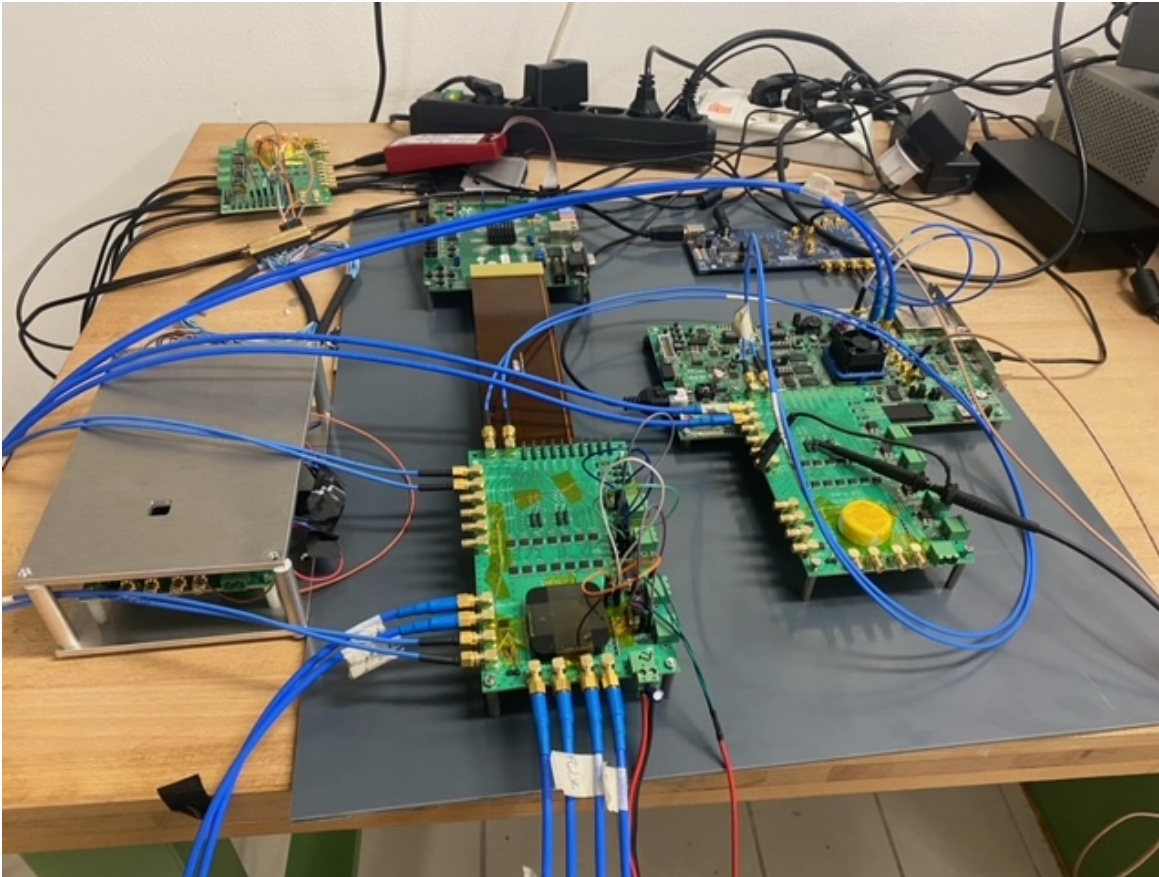
FPGA MODE (Boards T1 & T2)

BIST Mode (Boards B1 & B2)

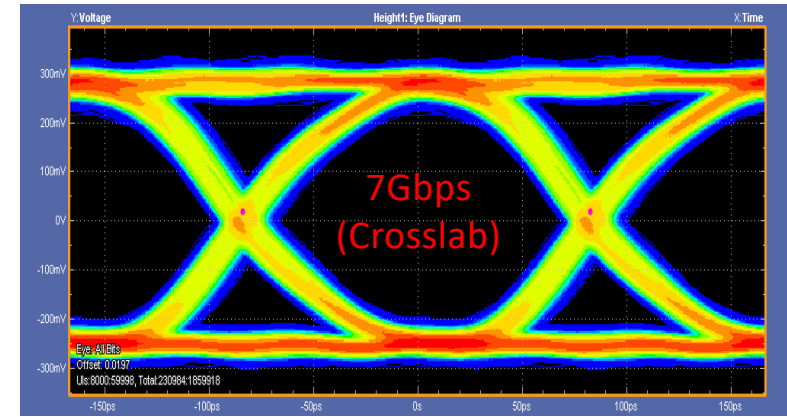
Test	Eye Characterization	Serializer Test	Test	Eye Characterization	Serializer Test
Setup 1 (1-2 Gbps)	K Mode => 1,2 Gbps	K,1P,4P Modes => 2Gbps PRBS Mode => ?	Setup 1 (1-2 Gbps)	K Mode => 1,2 Gbps	BIST Test => OK BIST Mode => OK
Setup 2 (2-5 Gbps)	K Mode => 2,3,4,5 Gbps	K,1P,4P Modes => 5Gbps PRBS Mode => ?	Setup 2 (2-5 Gbps)	K Mode => 2,3,4,5 Gbps	BIST Test => OK BIST Mode => OK
Setup 3 (5-10 Gbps)			Setup 3 (5-10 Gbps)	K Mode => 5,6 Gbps	BIST Test => ? BIST Mode => ?
Test	Eye Characterization	Serializer Test	Test	Eye Characterization	Serializer Test
Setup 1 (1-2 Gbps)	K Mode => 1,2 Gbps	K,1P,4P Modes => 2Gbps PRBS Mode => ?	Setup 1 (1-2 Gbps)	K Mode => ?	BIST Test => ? BIST Mode => ?
Setup 2 (2-5 Gbps)	K Mode => 2,3,4,5 Gbps	K,1P,4P Modes => 5Gbps PRBS Mode => ?	Setup 2 (2-5 Gbps)	K Mode => ?	BIST Test => ? BIST Mode => ?
Setup 3 (5-10 Gbps)	K Mode => 5,6 Gbps	K,1P,4P Modes => ? PRBS Mode => ?	Setup 3 (5-10 Gbps)	K Mode => ?	BIST Test => ? BIST Mode => ?

4 Test Boards initially assembled – DUT replaced in T1 and B2 (June 2023)

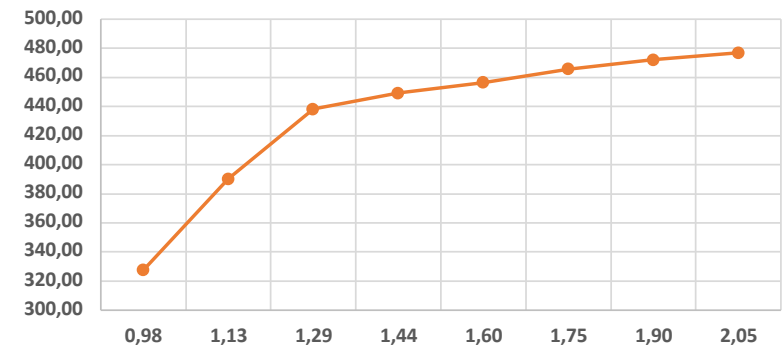
SER_V1 (Test and Characterization)



Test Setup ready for SEU test at LNL
Test Setup ready for SEU test at LNL



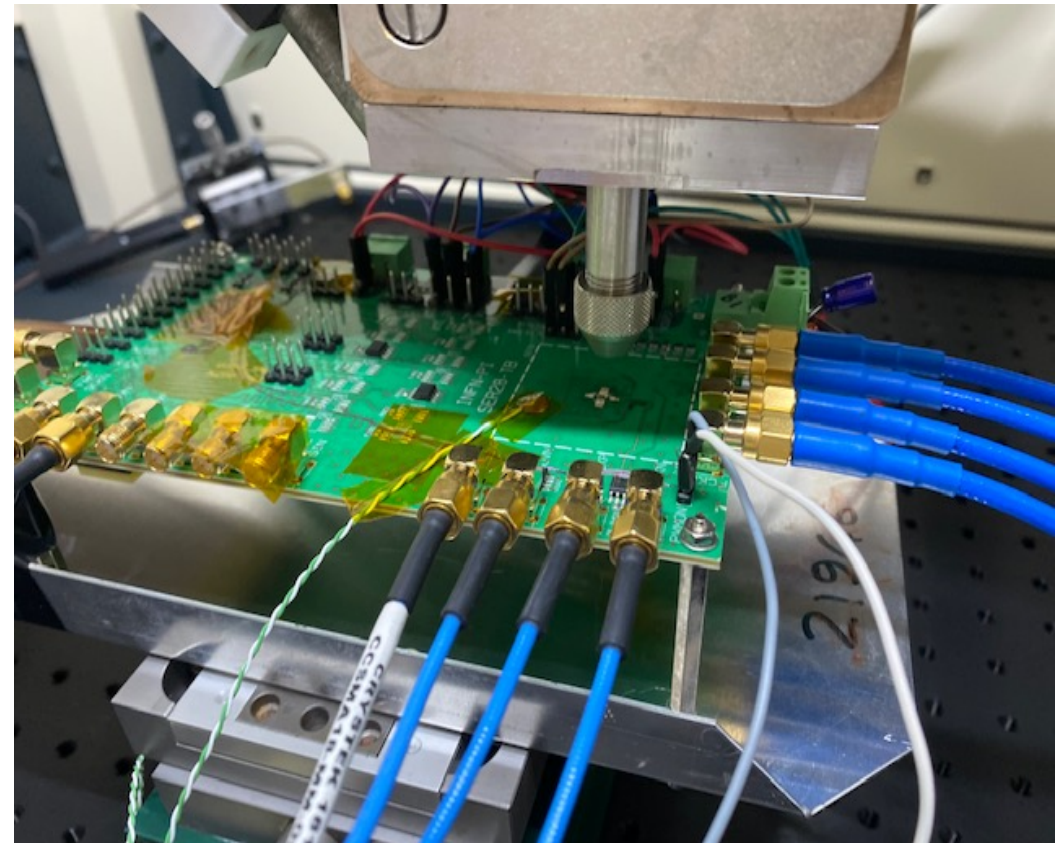
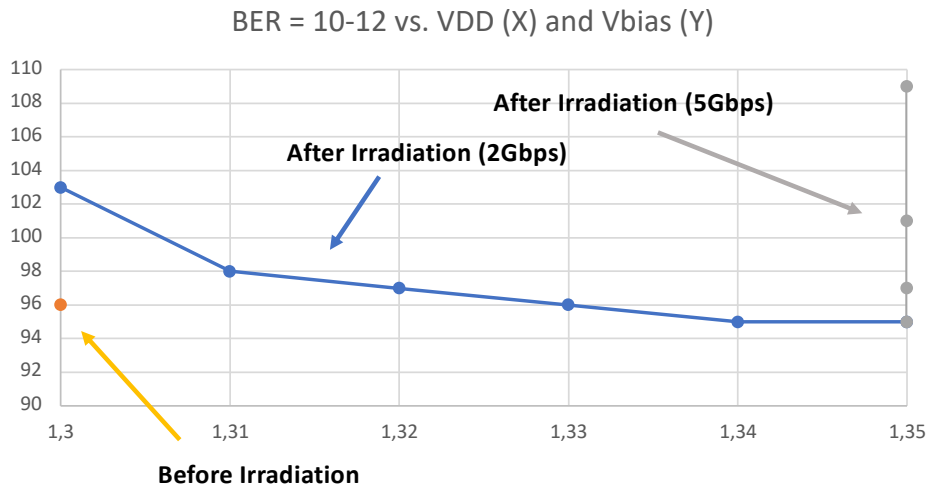
Eye Height (mV) vs. I_{bias} (mA)



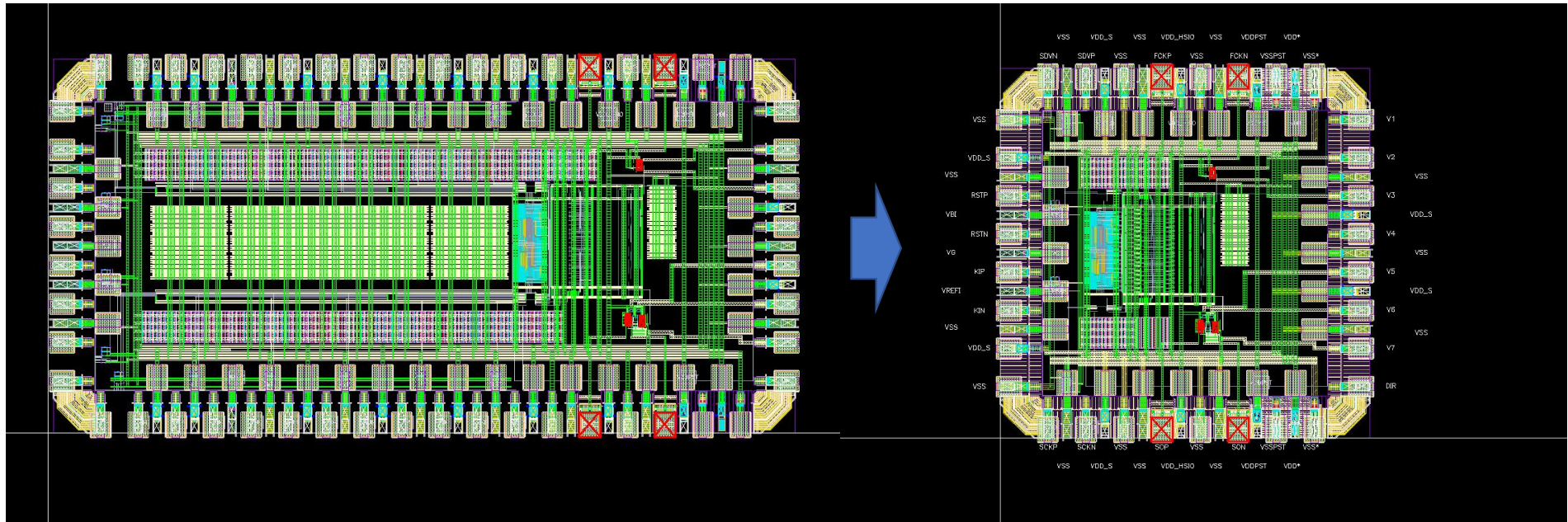
SER_V1 (Test and Characterization)

TID Test @ INFN-Pisa

- Dose Rate = 3.1 Mrad/h
 - V = 40KV
 - I = 40mA
- TID = 1.25Grad (17 days!)
- BER measured during and after irradiation
 - Data Rate = 2-5Gbps
 - Acquisition Time = 500s => BER = 10^{-12} (different Vbias and Vdd values)
- Small increase of BER (expected) recovered by bias adjustment



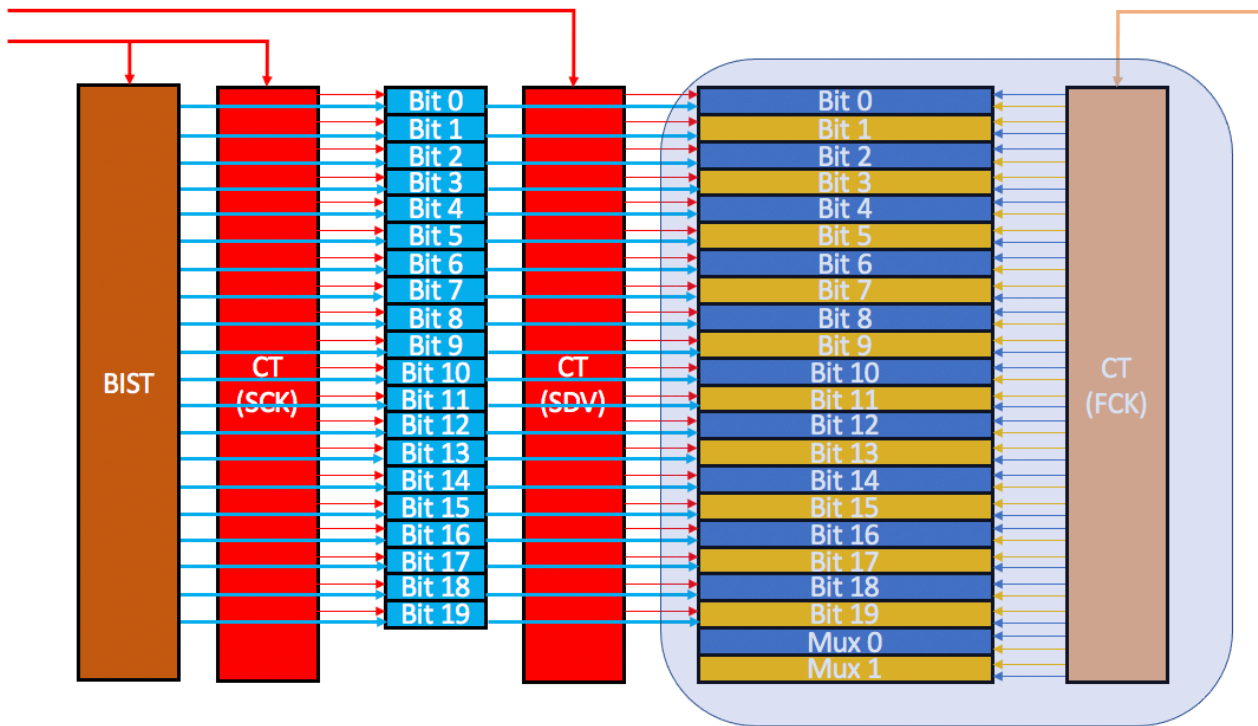
SER_V1 to SER_V2



SER_V1 (SDR - CML)

SER_V2 (DDR - CML)

SER28_V3 (CMOS)



Layout and PEX completed / post layout simulations performed

